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### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

KATO, et al.

**Application No.:** 

**TBD** 

Filed:

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March 10, 2004

For:

VACUUM PROCESSING APPARATUS AND OPERATING

METHOD THEREFOR

Expected

Group Art Unit:

3749

Expected

Examiner:

P. Wilson

## <u>INFORMATION DISCLOSURE STATEMENT</u> <u>UNDER 37 CFR § 1.97 AND § 1.98</u>

Mail Stop Patent Application Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450 March 10, 2004

Sir:

Pursuant to Applicants' duty of disclosure, enclosed please find a List of documents cited in connection with prior applications of the above-identified application. The listed documents were cited in at least one of the following U.S. patent applications, for which benefit has been claimed under 35 USC 120 in the above-identified application:

- (1) Application No. 10/682,901, filed October 14, 2003;
- (2) Application No. 09/766,975, filed January 23, 2001, now U.S. Patent No. 6,655,044, issued December 2, 2003;

- (3) Application No. 09/461,432, filed December 16, 1999, now U.S. Patent No. 6,330,755, issued December 18, 2001;
- (4) Application No. 09/177,495, filed October 23, 1998, now U.S. Patent No. 6,012,235, issued January 11, 2000;
- (5) Application No. 09/061,062, filed April 16, 1998, now U.S. Patent No. 5,950,330, issued September 14, 1999;
- (6) Application No. 07/751,951, filed August 29, 1991, now U.S. Patent No. 5,314,509, issued May 24, 1994;
- (7) Application No. 08/096,256, filed July 26, 1993, now U.S. Patent No. 5,349,762, issued September 27, 1994;
- (8) Application No. 08/443,039, filed May 17, 1995, now U.S. Patent No. 5,553,396, issued September 10, 1996;
- (9) Application No. 08/593,870, filed January 30, 1996, now U.S. Patent No. 5,661,913, issued September 2, 1997;
- (10) Application No. 08/302,443, filed September 9, 1994, now U.S. Patent No. 5,457,896, issued October 17, 1995; and
- (11) Application No. 08/882,731, filed June 26, 1997, now U.S. Patent No. 5,784,799, issued July 28, 1998.

In particular, note that each of these listed documents cited in connection with prior applications, was cited in Application No. 10/682,901, filed October 14, 2003.

The listed documents have been cited in connection with at least one prior application of the above-identified application for which priority has been claimed under 35 USC 120; accordingly, copies of the listed documents are not enclosed.

Of the listed documents, attention is particularly directed to U.S. Patent No. 4,923,584 and Japanese Patent Document No. 63-153270. Please note that a partial English translation of Japanese Patent Document No. 63-153270 has been submitted in prior applications of the above-identified application, for which priority has been claimed under 35 USC 120. In addition, a full English translation of Japanese Patent Document No. 63-153270 has previously been submitted in a prior application of the above-identified application being relied upon under 35 USC §120.

In addition, note the following comments concerning various of the listed documents which are not in English. JP No. 2-61064 corresponds to U.S. Patent No. 4,969,790 (also listed), and relates to a merry-go-round system. JP No. 1-310553 relates to a single chamber. JP No. 1-251734 relates to a vacuum cassette. JP No. 62-44571 relates to an ion implantor. JP No. 62-50463 relates to a sputtering device; and JP No. 2-106037 relates to a single chamber device. JP No. 57-29577 relates to a sputtering device. In "Semiconductor Equipment Association of Japan", a load lock chamber is defined.

This Information Disclosure Statement is being submitted concurrently with the filing of the above-identified application. Accordingly, it is respectfully submitted that requirements of 37 CFR 1.97(b) are satisfied.

To the extent that the enclosed documents are not in English, it is respectfully submitted that the requirements of 37 CFR 1.98(a)(3) are satisfied by the previously submitted abstracts of various of the documents not in English, partial English translations of various of the documents not in English, the foregoing comments, and the submitted full English translation of JP No. 63-153270.

In view of all of the foregoing, it is respectfully submitted that all applicable requirements of 37 CFR 1.97 and 1.98 have been satisfied, in connection with the documents on the enclosed List. Accordingly, consideration of the listed documents, upon examination of the above-identified application, is respectfully requested.

To the extent necessary, Applicants petition for an extension of time under 37 CFR § 1.136. Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to the Deposit Account No. 01-2135 (Case No. 503.30414C56) and please credit any excess fees to such Deposit Account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP

William I. Solomon

Registration No. 28,565

1300 North Seventeenth Street

**Suite 1800** 

Arlington, VA 22209 Tel.: 703-312-6600

Fax.: 703-312-6666

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**FORM PTO-1449** U.S. Department of Commerce (Rev. 4/92)

Patent and Trademark Office

**INFORMATION DISCLOSURE** STATEMENT BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO.

APPLICATION NO.

**TBD** 

520.30414C56

APPLICANT KATO, et al.

**FILING DATE** March 10, 2004

**EXPECTED GROUP** 3749

**U.S. PATENT DOCUMENTS** 

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R.P.H. Chang, "Multipurpose plasma reactor for materials research and processing", J. Vac. Sci. Technol., Vol. 14, No. 1, Jan./Feb. 1977, pages 278-280.

Semiconductor Equipment Association of Japan, "Terminological Dictionary of Semiconductor Equipment", front, table, page 183, back, Nov. 20, 1987.

Semiconductor Equipment Association of Japan, "Semiconductor News", Vol. 4, pp. 38-43, April 10, 1987 (w/ translation).

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<sup>\*</sup> PTR (partial translation) - FTR (full translation) - ABS (abstract)

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AV	JP application No. 2000-05449. Notification of Reasons for Refusal 0.6.00 (TD)
AW	JP application No. 2000-054450. Notification of Reasons for Refusal 9.6.00 (TP)
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<sup>\*</sup> PTR (partial translation) - FTR (full translation) - ABS (abstract)

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<sup>\*</sup> PTR (partial translation) - FTR (full translation) - ABS (abstract)

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AP	57-29577	2-17-82	Japan			ABS	
AQ	62-207866	9-12-87	Japan			ABS	
AR	59-094435	5-31-84	Japan			FTR	
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<sup>\*</sup> PTR (partial translation) - FTR (full translation) - ABS (abstract)

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Form PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	<b>ATTY. DKT. NO.</b> 520.30415C56	SERIAL NO. TBd		
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	AV	Semicon News, April 1987 (pp. 38-43) (PTR)
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<sup>\*</sup> PTR (partial translation) - FTR (full translation) - ABS (abstract)

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